LM1973 µPot 3-Channel 76dB Audio Attenuator with Mute

Check for Samples: LM1973

FEATURES

- **3-Wire Serial Interface**
- **Daisy-Chain Capability**
- **104dB Mute Attenuation**
- **Pop and Click Free Attenuation Changes**

APPLICATIONS

- **Automated Studio Mixing Consoles**
- **Music Reproduction Systems**
- **Sound Reinforcement Systems**
- **Electronic Music (MIDI)**
- **Personal Computer Audio Control**

KEY SPECIFICATIONS

- **Total Harmonic Distortion + Noise: 0.003 % (max)**
- **Frequency response: 100 kHz (−3dB) (min)**
- **Attenuation range (excluding mute): 76 dB (typ)**
- **Differential attenuation: ±0.25 dB (max)**
- **Signal-to-noise ratio (ref. 4 Vrms): 110 dB (min)**
- **Channel separation: 110 dB (typ)**

DESCRIPTION

The LM1973 is a digitally controlled 3-channel 76dB audio attenuator fabricated on a CMOS process. Each channel has attenuation steps of 0.5dB from 0dB–15.5dB, 1.0dB steps from 16dB–47dB, and 2.0dB steps from 48dB– 76dB, with a mute function attenuating 104dB. Its logarithmic attenuation curve can be customized through software to fit the desired application.

The performance of a µPot is demonstrated through its excellent Signal-to-Noise Ratio, extremely low (THD+N), and high channel separation. Each µPot contains a mute function that disconnects the input signal from the output, providing a minimum attenuation of 96dB. Transitions between any attenuation settings are pop free.

The LM1973's 3-wire serial digital interface is TTL and CMOS compatible; receiving data that selects a channel and the desired attenuation level. The Data-Out pin of the LM1973 allows multiple µPots to be daisy-chained together, reducing the number of enable and data lines to be routed for a given application.

TYPICAL APPLICATION

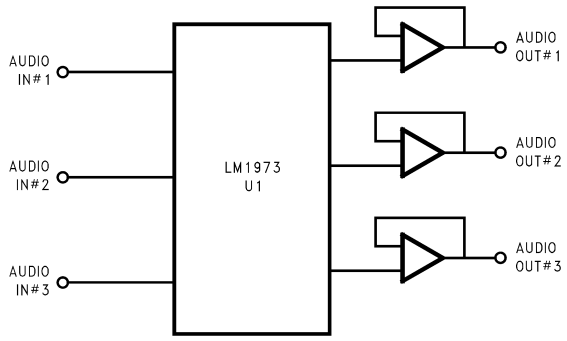


Figure 1. Typical Audio Attenuator Application Circuit

CONNECTION DIAGRAM

Top View

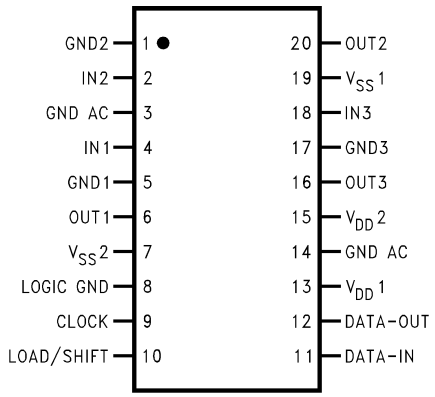


Figure 2. PDIP and SOIC Packages
See Package Numbers NFH0020A and DW0020B

These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

ABSOLUTE MAXIMUM RATINGS (1)(2)(3)

Supply Voltage (V_{DD}–V_{SS})		15V
Voltage at Any Pin		V_{SS} − 0.2V to V_{DD} + 0.2V
Power Dissipation (4)		150 mW
ESD Susceptibility (5)		1800V
Junction Temperature		150°C
Soldering Information	NFH0020A Package (10 sec.)	+260°C
Storage Temperature		−65°C to +150°C

(1) All voltages are measured with respect to GND (pins 1, 3, 5, 14, 17), unless otherwise specified.
(2) *Absolute Maximum Ratings* indicate limits beyond which damage to the device may occur. *Operating Ratings* indicate conditions for which the device is functional. *Electrical Characteristics* state DC and AC electrical specifications under particular test conditions and specific performance limits. This assumes that the device is within the Operating Ratings. The typical value is a good indication of device performance.
(3) If Military/Aerospace specified devices are required, please contact the Texas Instruments Sales Office/ Distributors for availability and specifications.
(4) The maximum power dissipation must be derated at elevated temperatures and is dictated by T_{JMAX}, θ_{JA}, and the ambient temperature T_A. The maximum allowable power dissipation is PD = $(T_{JMAX} - T_A)/\theta_{JA}$ or the number given in the Absolute Maximum Ratings, whichever is lower. For the LM1973N, T_{JMAX} = +150°C, and the typical junction-to-ambient thermal resistance, when board mounted, is 65°C/W.
(5) Human body model, 100 pF discharged through a 1.5 kΩ resistor.

OPERATING RATINGS (1)(2)

		T_{MIN}	T_A	T_{MAX}
Temperature Range	$T_{MIN} \le T_A \le T_{MAX}$	0°C	$\le T_A$	≤ +70°C
Supply Voltage (V_{DD} − V_{SS})				4.5V to 12V

(1) *Absolute Maximum Ratings* indicate limits beyond which damage to the device may occur. *Operating Ratings* indicate conditions for which the device is functional. *Electrical Characteristics* state DC and AC electrical specifications under particular test conditions and specific performance limits. This assumes that the device is within the Operating Ratings. The typical value is a good indication of device performance.
(2) All voltages are measured with respect to GND (pins 1, 3, 5, 14, 17), unless otherwise specified.

ELECTRICAL CHARACTERISTICS (1)(2)

The following specifications apply for all channels with V_{DD} = +6V, V_{SS} = −6V, V_{IN} = 5.5 Vpk, and f = 1 kHz, unless otherwise specified. Limits apply for T_A = 25°C. Digital inputs are TTL and CMOS compatible.

Parameter		Test Conditions	LM1973		Units (Limits)
			Typical (3)	Limit (4)	
I_S	Supply Current	Inputs are AC Grounded	3	5	mA (max)
THD+N	Total Harmonic Distortion plus Noise	V_{IN} = 0.5 Vpk at 0dB Attenuation	0.0008	0.003	% (max)
XTalk	Crosstalk (Channel Separation)	0dB Attenuation for V_{IN}	110		dB
	(5)	V_{CH} measured at −76dB			
SNR	Signal-to-Noise Ratio	Inputs are AC Grounded at −12dB Attenuation A-Weighted	120	110	dB (min)
A_M	Mute Attenuation		104	96	dB (min)
	Attenuation Step Size Error	0dB to −16dB		±0.05	dB (max)
		−17dB to −48dB		±0.1	dB (max)
		−49dB to −76dB		±0.25	dB (max)
	Absolute Attenuation Error	Attenuation at 0dB	0.01	0.5	dB (min)
		Attenuation at −20dB	19.8	19.0	dB (min)
		Attenuation at −40dB	39.5	38.5	dB (min)
		Attenuation at −60dB	59.3	58.0	dB (min)
		Attenuation at −76dB	74.5	73.0	dB (min)
	Channel-to-Channel Attenuation	Attenuation at 0dB, −20dB, −40dB, −60dB		±0.5	dB (max)
	Tracking Error	Attenuation at −76dB		±0.75	dB (max)
I_{LEAK}	Analog Input Leakage Current	Inputs are AC Grounded	10.0	100	nA (max)
R_{IN}	AC Input Impedance	Pins 2, 4, 18, V_{IN} = 1.0 Vpk, f = 1 kHz	40	20	kΩ (min)
				60	kΩ (max)
I_{IN}	Input Current	at Pins 9, 10, 11 at 0V < V_{IN} < 5V	1.0	±100	nA (max)
f_{CLK}	Clock Frequency		3	2	MHz (max)
V_{IH}	High-Level Input Voltage	at Pins 9, 10, 11		2.0	V (min)
V_{IL}	Low-Level Input Voltage	at Pins 9, 10, 11		0.8	V (max)
	Data-Out Levels (Pin 12)	V_{DD} = 6V, V_{SS} = 0V		0.1	V (max)
				5.9	V (min)

(1) *Absolute Maximum Ratings* indicate limits beyond which damage to the device may occur. *Operating Ratings* indicate conditions for which the device is functional. *Electrical Characteristics* state DC and AC electrical specifications under particular test conditions and specific performance limits. This assumes that the device is within the Operating Ratings. The typical value is a good indication of device performance.
(2) All voltages are measured with respect to GND (pins 1, 3, 5, 14, 17), unless otherwise specified.
(3) Typicals are measured at 25°C and represent the parametric norm.
(4) Limits are specified to TI's AOQL (Average Output Quality Level).
(5) At the present time the Crosstalk measurement is specified as a typical only, which is due to a hardware limitation of the automated test equipment.

TEST CIRCUIT DIAGRAMS

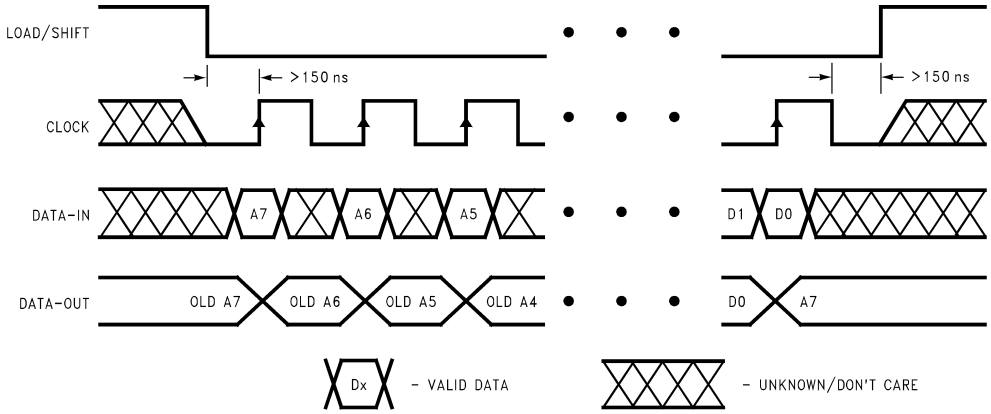


Figure 3. Timing Diagram

PIN DESCRIPTIONS

Signal Ground (1, 5, 17): Each input has its own independent ground, GND1, GND2, and GND3.

Signal Input (2, 4, 18): There are 3 independent signal inputs, IN1, IN2, and IN3.

Signal Output (6, 16, 20): There are 3 independent signal outputs, OUT1, OUT2, and OUT3.

Voltage Supply (13, 15):

Voltage Supply (7, 19): Negative voltage supply pins, V_{SS1} and V_{SS2}. To be tied to ground in a single supply configuration.

AC Ground (3, 14): These two pins are not physically connected to the die in any way (i.e., No bondwires). These pins must be AC grounded to prevent signal coupling between any of the pins nearby. Pin 14 should be connected to pins 13 and 15 for ease of wiring and the best isolation.

Logic Ground (8): Digital signal ground for the interface lines; CLOCK, LOAD/SHIFT, DATA-IN and DATA-OUT.

Clock (9): The clock input accepts a TTL or CMOS level signal. The clock input is used to load data into the internal shift register on the rising edge of the input clock waveform.

Load/Shift (10): The load/shift input accepts a TTL or CMOS level signal. This is the enable pin of the device, allowing data to be clocked in while this input is low (0V).

Data-In (11): The data-in input accepts a TTL or CMOS level signal. This pin is used to accept serial data from a microcontroller that will be latched and decoded to change a channel's attenuation level.

Data-Out (12): This pin is used in daisy-chain mode where more than one µPot is controlled via the same data line. As the data is clocked into the chain from the µC, the preceding data in the shift register is shifted out the DATA-OUT pin to the next µPot in the chain or to ground if it is the last µPot in the chain. The LOAD/SHIFT line goes high once all of the new data has been shifted into each of its respective registers.

TYPICAL PERFORMANCE CHARACTERISTICS

Supply Current vs Supply Voltage

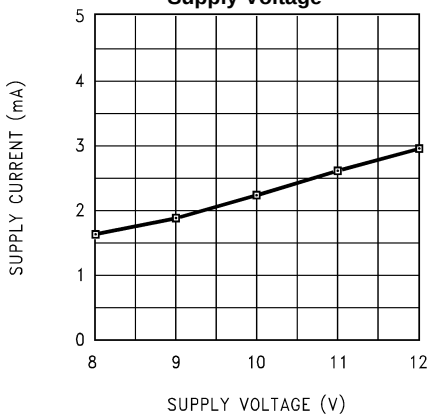


Figure 4.

Supply Current vs Temperature

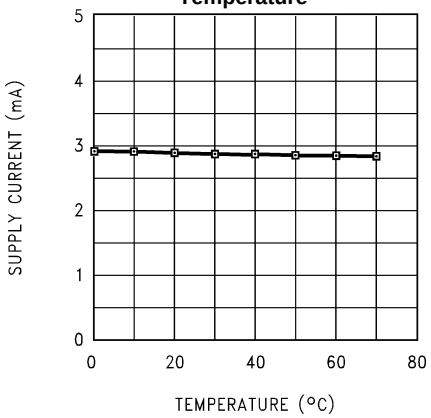


Figure 5.

Noise Floor Spectrum by FFT Amplitude vs Frequency

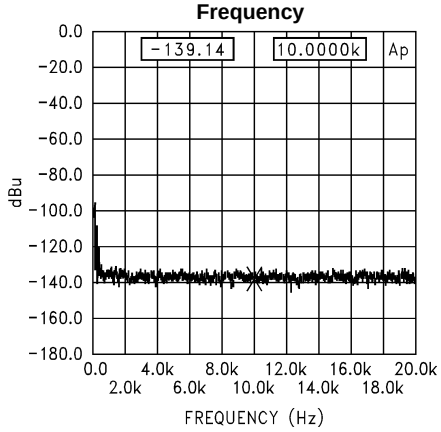


Figure 6.

THD vs Freq by FFT $V_{DD} - V_{SS} = 12V$

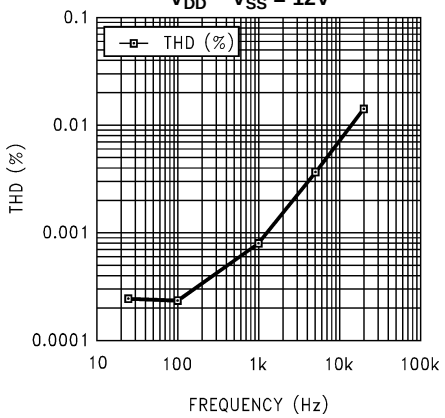


Figure 7.

THD vs V_{OUT} at 1 kHz by FFT $V_{DD} - V_{SS} = 12V$

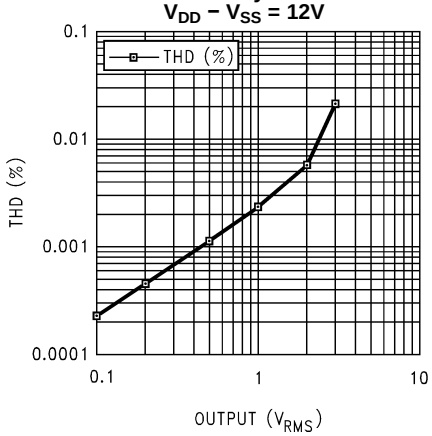


Figure 8.

Crosstalk Test

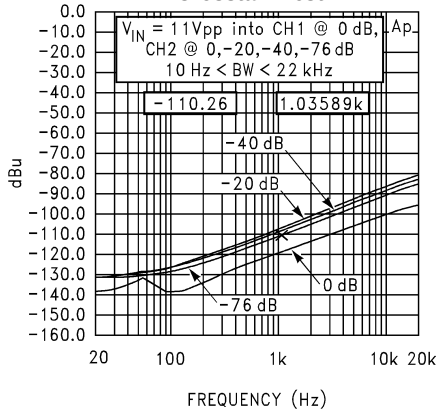


Figure 9.

TYPICAL PERFORMANCE CHARACTERISTICS (continued)

THD + N vs Frequency and Amplitude

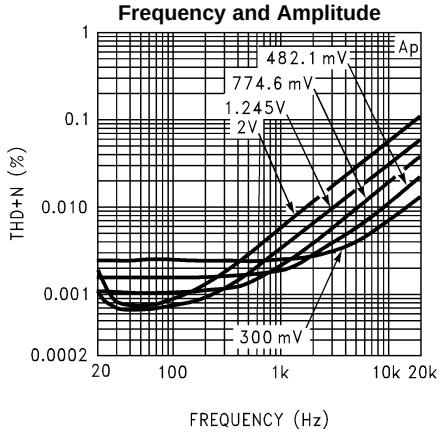


Figure 10.

FFT of 1 kHz THD

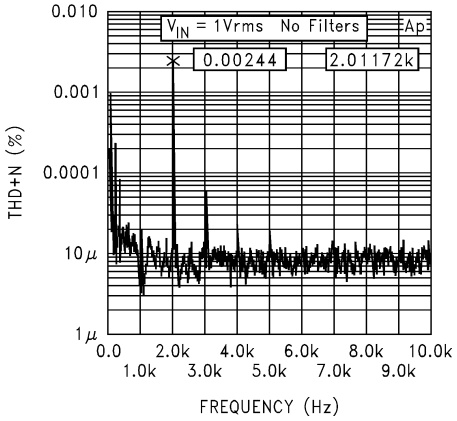


Figure 11.

FFT of 20 kHz THD

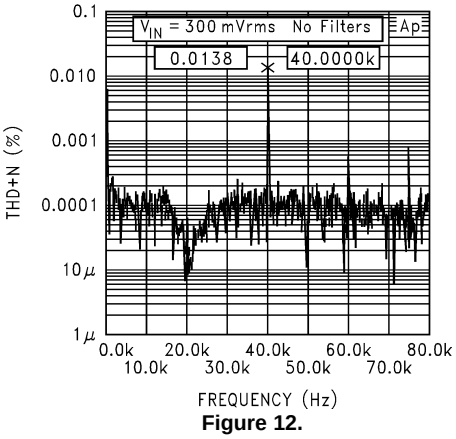


Figure 12.

THD + N vs Amplitude f = 20 Hz, V_{DD} = ±6V V_{IN} into CH1 at 0 dB

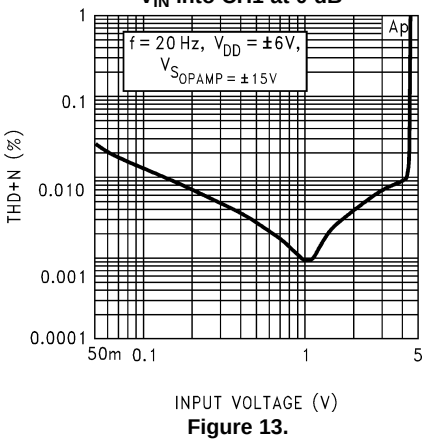


Figure 13.

THD + N vs Amplitude f = 1 kHz, V_{DD} = ±6V V_{IN} into CH1 at 0 dB

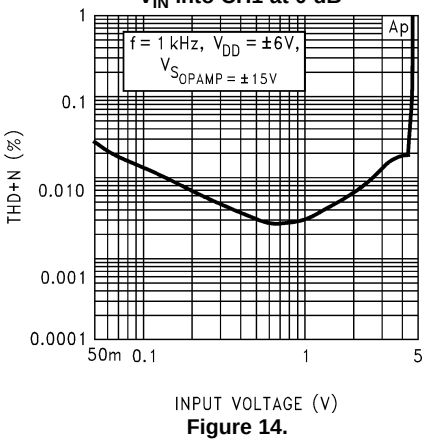


Figure 14.

THD + N vs Amplitude f = 20 kHz, V_{DD} = ±6V V_{IN} into CH1 at 0 dB

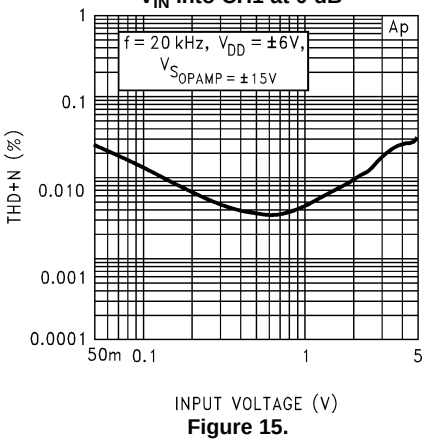


Figure 15.

APPLICATION INFORMATION

ATTENUATION STEP SCHEME

The fundamental attenuation step scheme for the LM1973 µPot is shown in Figure 16. This attenuation step scheme, however, can be changed through programming techniques to fit different application requirements. One such example would be a constant logarithmic attenuation scheme of 2dB steps for a panning function as shown in Figure 18. The only restriction to the customization of attenuation schemes are the given attenuation levels and their corresponding data bits shown in Table 1. The device will change attenuation levels only when a channel address is recognized. When recognized, the attenuation level will be changed corresponding to the data bits shown in Table 1. As shown in Figure 19, an LM1973 can be configured with a mono audio signal level control and with a panning control which separates the mono signal into left and right channels. This circuit may utilize the fundamental attenuation scheme of the LM1973 for the level control, but also possess a constant 2dB panning control for the left and right channels as stated earlier.

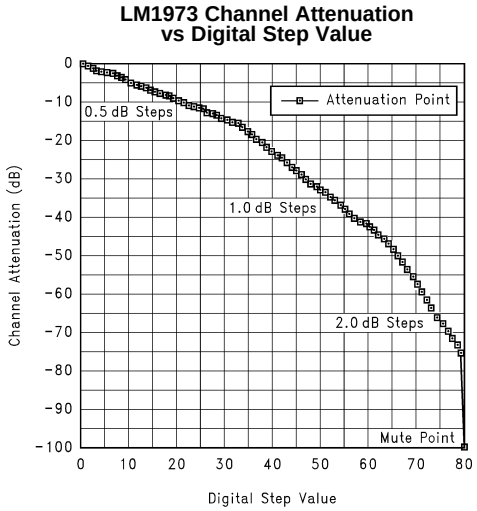


Figure 16.

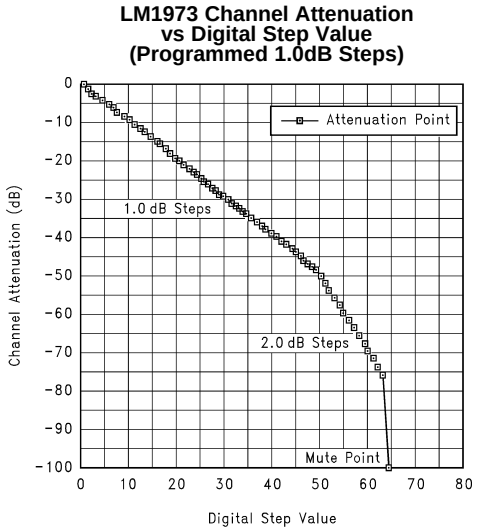


Figure 17. LM1973 1.0dB and 2.0dB Attenuation Step Scheme

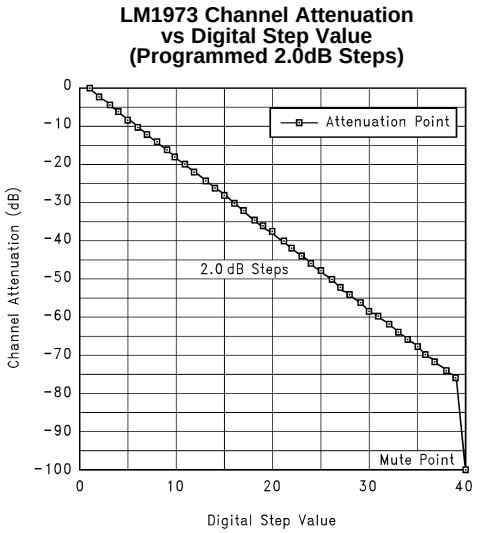


Figure 18. LM1973 2.0dB Attenuation Step Scheme

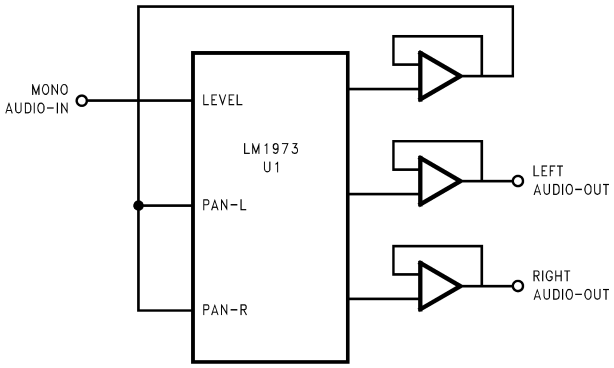


Figure 19. Mono Level Control with Panning Circuit

INPUT IMPEDANCE

The input impedance of a µPot is constant at a nominal 40 kΩ. To eliminate any unwanted DC components from propagating through the device it is common to use 1 µF input coupling caps. This is not necessary, however, if the dc offset from the previous stage is negligible. For higher performance systems, input coupling caps are preferred.

OUTPUT IMPEDANCE

The output of a µPot varies typically between 25 kΩ and 35 kΩ and changes nonlinearly with step changes. Since a µPot is made up of a resistor ladder network with a logarithmic attenuation, the output impedance is nonlinear. Due to this configuration, a µPot cannot be considered as a linear potentiometer, but can be considered only as a logarithmic attenuator.

It should be noted that the linearity of a µPot cannot be measured directly without a buffer because the input impedance of most measurement systems is not high enough to provide the required accuracy. Due to the low impedance of the measurement system, the output of the µPot would be loaded down and an incorrect reading will result. To prevent loading from occurring, a JFET input op amp should be used as the buffer/amplifier. The performance of a µPot is limited only by the performance of the external buffer/amplifier.

MUTE FUNCTION

One major feature of a µPot is its ability to mute the input signal to an attenuation level of 104dB as shown in Figure 16. This is accomplished internally by physically isolating the output from the input while also grounding the output pin through approximately 2 kΩ.

The mute function is obtained during power-up of the device or by sending any binary data of 01001111 and above (to 11111111) serially to the device. The device may be placed into mute from a previous attenuation setting by sending any of the above data. This allows the designer to place a mute button onto his system which could cause a microcontroller to send the appropriate data to a µPot and thus mute any or all channels. Since this function is achieved through software, the designer has a great amount of flexibility in configuring the system.

DC INPUTS

Although the µPot was designed to be used as an attenuator for signals within the audio spectrum, the device is capable of tracking an input DC voltage. The device will track DC voltages to a diode drop above each supply rail.

One point to remember about DC tracking is that with a buffer at the output of the µPot, the resolution of DC tracking will depend upon the gain configuration of that output buffer and its supply voltage. It should also be remembered that the output buffer's supply voltage does not have to be the same as the µPot's supply voltage. This could allow for more resolution when DC tracking.

SERIAL DATA FORMAT

The LM1973 uses a 3-wire serial communication format that is easily controlled by a microcontroller. The timing for the 3-wire set, comprised of DATA-IN, CLOCK, and LOAD/SHIFT is shown in Figure 3. Figure 22 exhibits in block diagram form how the digital interface controls the tap switches which select the appropriate attenuation level. As depicted in Figure 3, the LOAD/SHIFT line is to go low at least 150 ns before the rising edge of the first clock pulse and is to remain low throughout the transmission of each set of 16 data bits. The serial data is comprised of 8 bits for channel selection and 8 bits for attenuation setting. For both address data and attenuation setting data, the MSB is sent first and the 8 bits of address data are to be sent before the 8 bits of attenuation data. Please refer to Figure 20 to confirm the serial data format transfer process.

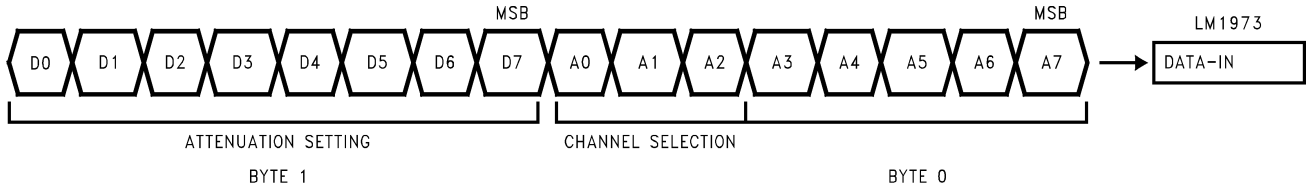


Figure 20. Serial Data Format Transfer Process

Table 1. LM1973 Micropot Attenuator Register Set Description

MSB: LSB	
Address Register (Byte 0)	
0000 0000	Channel 1
0000 0001	Channel 2
0000 0010	Channel 3
Data Register (Byte 1)	
Contents	**Attenuation Level dB**
0000 0000	0.0
0000 0001	0.5
0000 0010	1.0
0000 0011	1.5
: : : : :	: :
0001 1110	15.0
0001 1111	15.5
0010 0000	16.0
0010 0001	17.0
0010 0010	18.0

Table 1. LM1973 Micropot Attenuator Register Set Description (continued)

MSB: LSB	
Address Register (Byte 0)	
: : : : :	: :
0011 1110	46.0
0011 1111	47.0
0100 0000	48.0
0100 0001	50.0
0100 0010	52.0
: : : : :	: :
0100 1100	72.0
0100 1101	74.0
0100 1110	76.0
0100 1111	100.0 (Mute)
0101 0000	100.0 (Mute)
: : : : :	: :
1111 1110	100.0 (Mute)
1111 1111	100.0 (Mute)

µPot SYSTEM ARCHITECTURE

The µPot's digital interface is essentially a shift register, where serial data is shifted in, latched, and then decoded. As new data is shifted into the DATA-IN pin, the previously latched data is shifted out the DATA-OUT pin. Once the data is shifted in, the LOAD/SHIFT line goes high, latching in the new data. The data is then decoded and the appropriate switch is activated to set the desired attenuation level for the selected channel. This process is continued each and every time an attenuation change is made. Each channel is updated, only, when that channel is selected for an attenuator change or the system is powered down and then back up again. When the µPot is powered up, each channel is placed into the muted mode.

µPot LADDER ARCHITECTURE

Each channel of a µPot has its own independent resistor ladder network. As shown in Figure 21, the ladder consists of multiple R1/R2 elements which make up the attenuation scheme. Within each element there are tap switches that select the appropriate attenuation level corresponding to the data bits in Table 1. It can be seen in Figure 21 that the input impedance for the channel is a constant value regardless of which tap switch is selected, while the output impedance varies according to the tap switch selected.

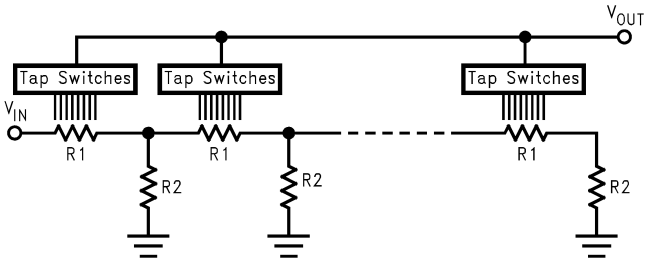


Figure 21. µPot Ladder Architecture

DIGITAL LINE COMPATIBILITY

The µPot's digital interface section is compatible with either TTL or CMOS logic due to the shift register inputs acting upon a threshold voltage of 2 diode drops or approximately 1.4V.

DIGITAL DATA-OUT PIN

The DATA-OUT pin is available for daisy-chain system configurations where multiple µPots will be used. The use of the daisy-chain configuration allows the system designer to use only one DATA and one LOAD/SHIFT line per chain, thus simplifying PCB trace layouts.

In order to provide the highest level of channel separation and isolate any of the signal lines from digital noise, the DATA-OUT pin should be terminated through a 2 kΩ resistor if not used. The pin may be left floating, however, any signal noise on that line may couple to adjacent lines creating higher noise specs.

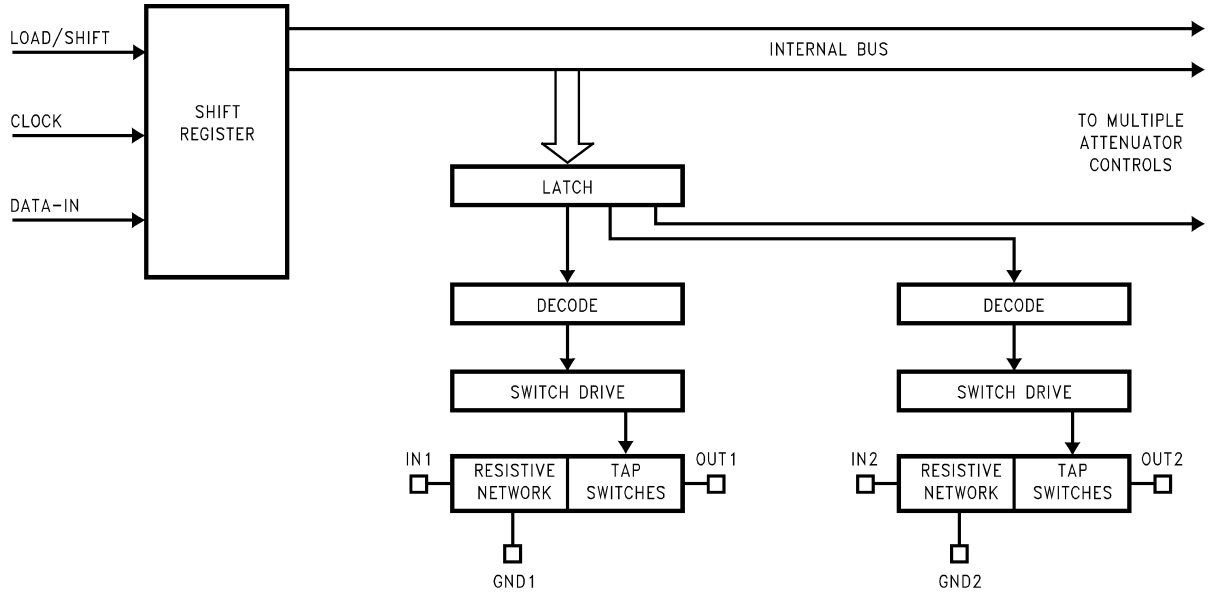


Figure 22. µPot System Architecture

DAISY-CHAIN CAPABILITY

Since the µPot's digital interface is essentially a shift register, multiple µPots can be programmed utilizing the same data and load/shift lines. As shown in Figure 24, for an n-µPot daisy-chain, there are 16n bits to be shifted and loaded for the chain. The data loading sequence is the same for n-µPots as it is for one µPot. First the LOAD/SHIFT line goes low, then the data is clocked in sequentially while the preceding data in each µPot is shifted out the DATA-OUT pin to the next µPot in the chain or to ground if it is the last µPot in the chain. Then the LOAD/SHIFT line goes high; latching the data into each of their corresponding µPots. The data is then decoded according to the address (channel selection) and the appropriate tap switch controlling the attenuation level is selected.

CROSSTALK MEASUREMENTS

The crosstalk of a µPot as shown in Figure 9 in the TYPICAL PERFORMANCE CHARACTERISTICS was obtained by placing a signal on one channel and measuring the level at the output of another channel of the same frequency. It is important to be sure that the signal level being measured is of the same frequency such that a true indication of crosstalk may be obtained. Also, to ensure an accurate measurement, the measured channel's input should be AC grounded through a 1 µF capacitor.

CLICKS AND POPS

So, why is that output buffer needed anyway? There are three answers to this question, all of which are important from a system point of view.

1. The first reason to utilize a buffer/amplifier at the output of a µPot is to ensure that there are no audible clicks or pops due to attenuation step changes in the device. If an on-board bipolar op amp had been used for the output stage, its requirement of a finite amount of DC bias current for operation would cause a DC voltage “pop” when the output impedance of the µPot changes. Again, this phenomenon is due to the fact that the output impedance of the µPot is changing with step changes and a bipolar amplifier requires a finite amount

of DC bias current for its operation. As the impedance changes, so does the DC bias current and thus there is a DC voltage “pop”.

2. Secondly, the µPot has no drive capability, so any desired gain needs to be accomplished through a buffer/non-inverting amplifer.
3. Third, the output of a µPot needs to see a high impedance to prevent loading and subsequent linearity errors from ocurring. A JFET input buffer provides a high input impedance to the output of the µPot so that this does not occur.

Clicks and pops can be avoided by using a JFET input buffer/amplifier such as an LF412ACN. The LF412 has a high input impedance and exhibits both a low noise floor and low THD+N throughout the audio spectrum which maintains signal integrity and linearity for the system. The performance of the system solution is entirely dependent upon the quality and performance of the JFET input buffer/amplifier.

LOGARITHMIC GAIN AMPLIFIER

The µPot is capable of being used in the feedback loop of an amplifier, however, as stated previously, the output of the µPot needs to see a high impedance in order to maintain its high performance and linearity. Again, loading the output will change the values of attenuation for the device. As shown in Figure 23, a µPot used in the feedback loop creates a logarithmic gain amplifier. In this configuration the attenuation levels from Table 1, now become gain levels with the largest possible gain value being 76dB. For most applications 76dB of gain will cause signal clipping to occur, however, because of the µPot's versatility the gain can be controlled through programming such that the clipping level of the system is never obtained. An important point to remember is that when in mute mode the input is disconnected from the output. In this configuration this will place the amplifier in its open loop gain state, thus resulting in severe comparator action. Care should be taken with the programming and design of this type of circuit. To provide the best performance, a JFET input amplifier should be used.

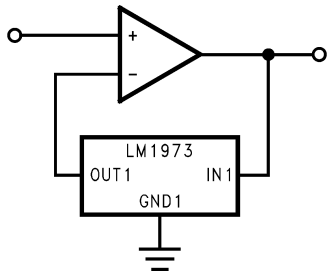


Figure 23. Digitally-Controlled Logarithmic Gain Amplifier Circuit

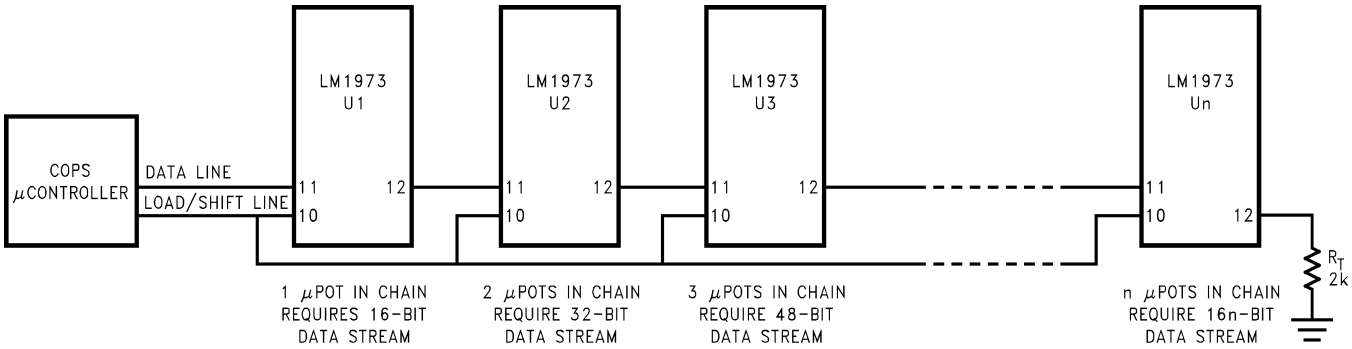


Figure 24. n-µPot Daisy-Chained Circuit

REVISION HISTORY

Changes from Revision A (March 2013) to Revision B	Page
• Changed layout of National Data Sheet to TI format	12

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
LM1973M/NOPB	ACTIVE	SOIC	DW	20	36	Green (RoHS & no Sb/Br)	CU SN	Level-3-260C-168 HR	0 to 70	LM1973M	Samples
LM1973MX/NOPB	ACTIVE	SOIC	DW	20	1000	Green (RoHS & no Sb/Br)	CU SN	Level-3-260C-168 HR	0 to 70	LM1973M	Samples

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.
TBD: The Pb-Free/Green conversion plan has not been defined.
Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.
Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.
Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

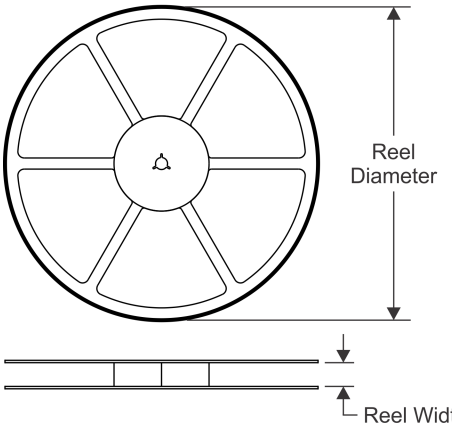
(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

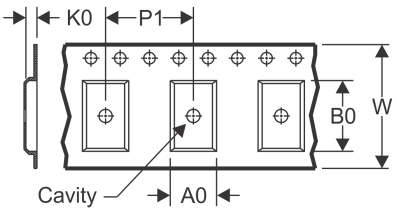
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

TAPE AND REEL INFORMATION

REEL DIMENSIONS

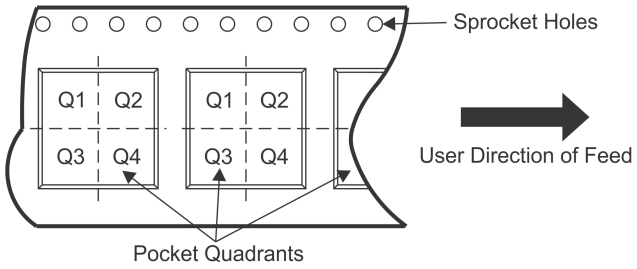


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

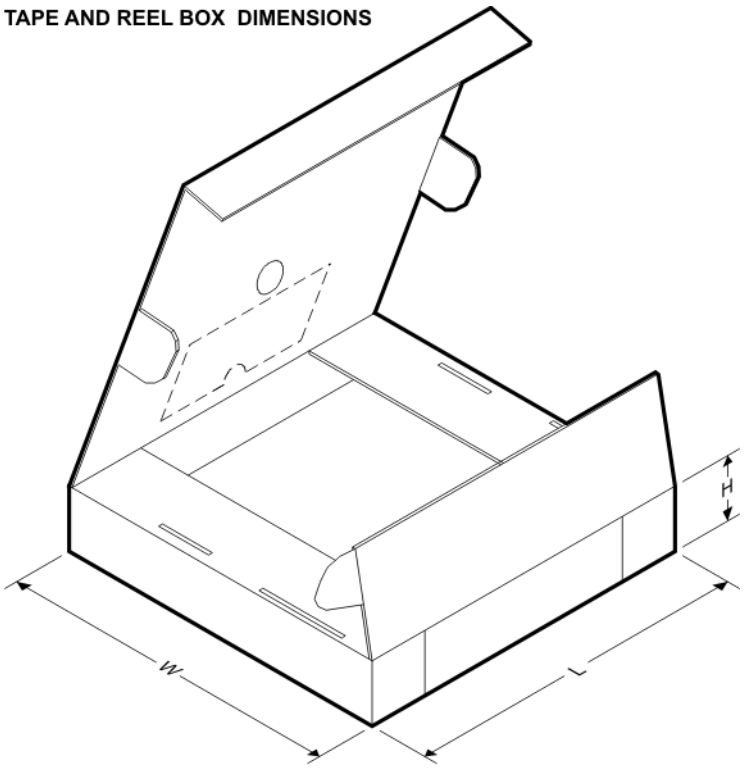
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

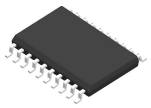
Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
LM1973MX/NOPB	SOIC	DW	20	1000	330.0	24.4	10.9	13.3	3.25	12.0	24.0	Q1

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
LM1973MX/NOPB	SOIC	DW	20	1000	367.0	367.0	45.0

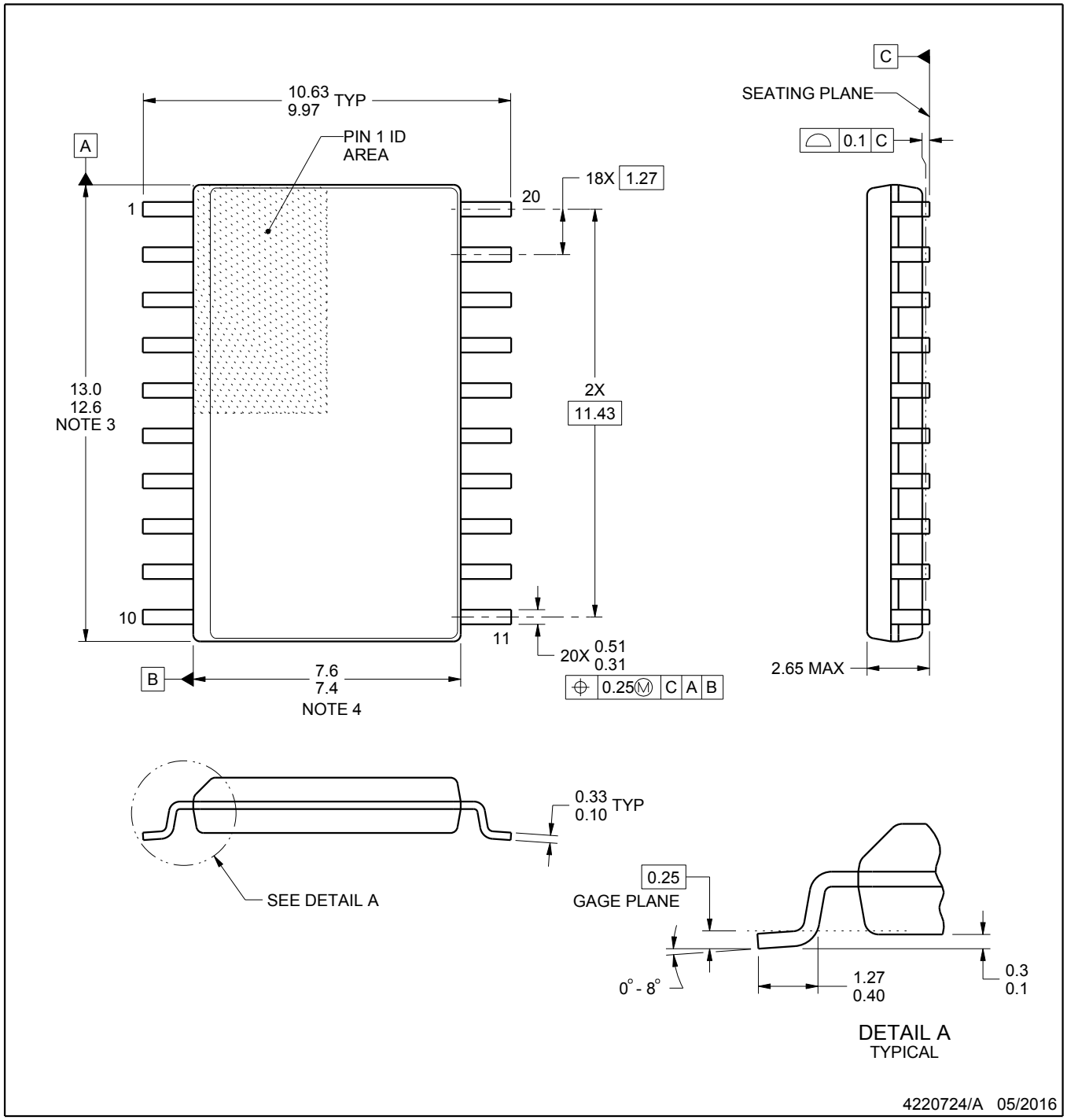


PACKAGE OUTLINE

DW0020A

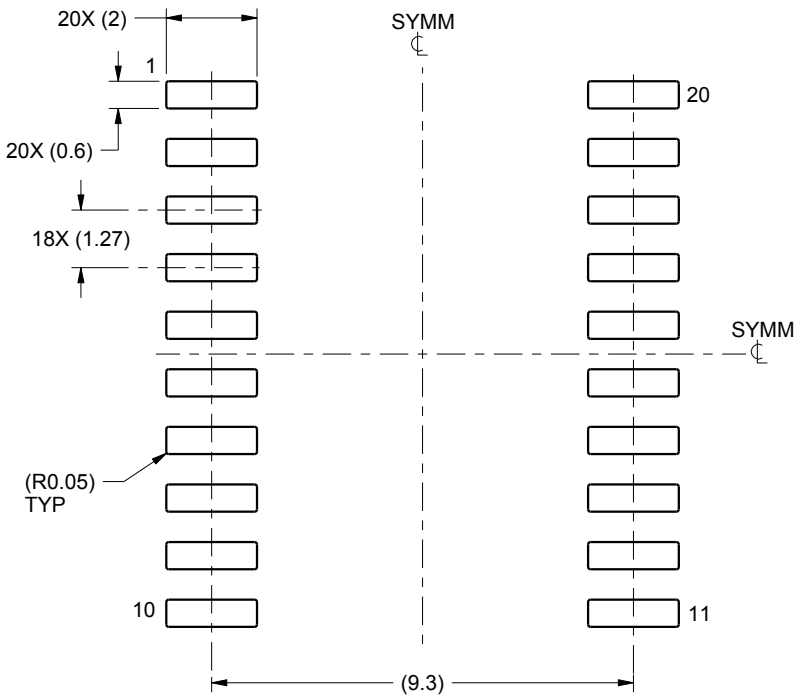
SOIC - 2.65 mm max height

SOIC

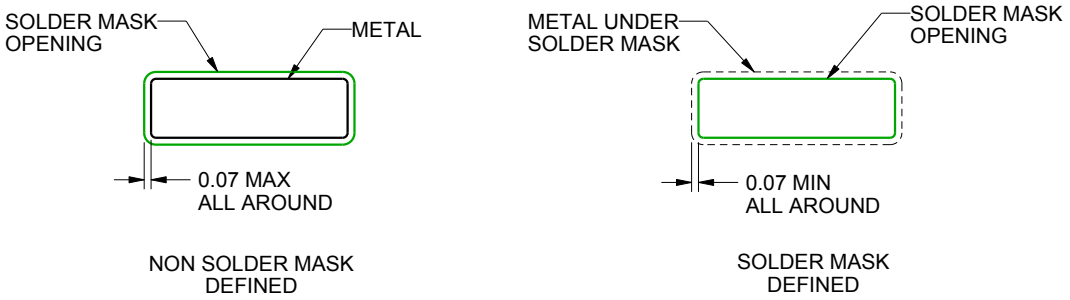


NOTES:

1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
5. Reference JEDEC registration MS-013.



LAND PATTERN EXAMPLE
SCALE:6X

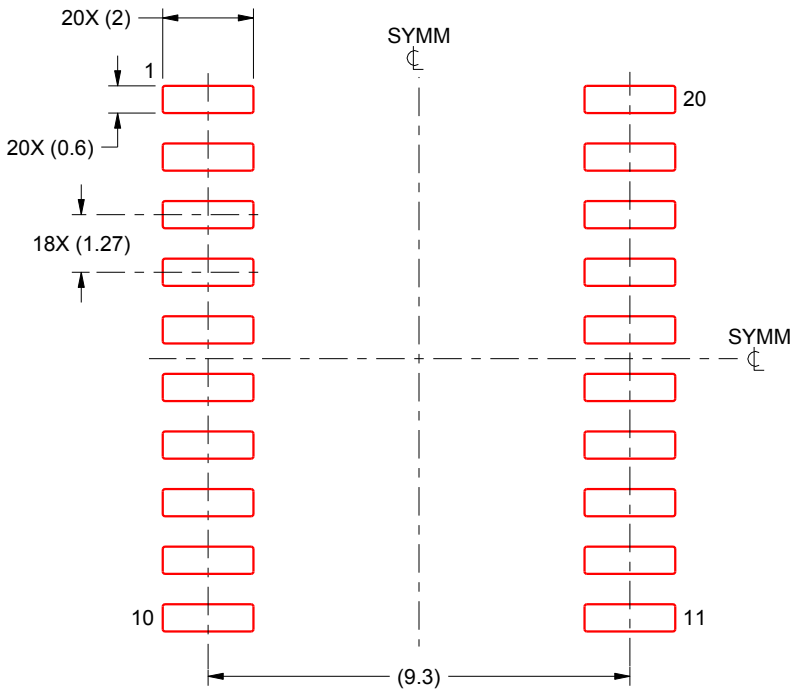


SOLDER MASK DETAILS

4220724/A 05/2016

NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE:6X

4220724/A 05/2016

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

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